

**Search Notes**

Application/Control No.

10/705,764

Examiner

Chuck Huynh

Applicant(s)/Patent under  
Reexamination

CLARK ET AL.

Art Unit

2683

**SEARCHED**

Class	Subclass	Date	Examiner
455	403	12/23/2005	CH
455	456	12/24/2005	CH
455	456.1	12/24/2005	CH
455	466	12/24/2005	CH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Class/Subclass/Text/Citations	12/23/2005	CH